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**INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION**  
Generic Copy

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**08-MAR-2004**

**SUBJECT: ON Semiconductor Initial Product/Process Change Notification #13335**

**TITLE: Dual Source Assembly/Test for Case-77 Thyristors at Mingxin**

**EFFECTIVE DATE: 09-Jul-2004**

**AFFECTED CHANGE CATEGORY:**

Subcontractor Assembly/Test Site

**AFFECTED PRODUCT DIVISION:** Discretes Products

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact Sales Office or Dave Culbertson <RAM140@onsemi.com>

**NOTIFICATION TYPE:**

Initial Product/Process Change Notification (IPCEN)

First change notification sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.

The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN).

This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 60 days prior to implementation of the change.

**DESCRIPTION AND PURPOSE:**

This is the Initial Notification announcing ON Semiconductor is qualifying MingXin Microelectronics in Ningbo, China as an additional site for the assembly and test of the Case-77 (T0-225AA Type) Thyristor products. MingXin Microelectronics is an ISO9002 certified site and currently assembles and tests Bipolar products for ON Semiconductor.

**QUALIFICATION PLAN:**

Lot 1, 2N6073B

Lot 2,3: C106M

High Humidity High Temperature Reverse Bias: Ta=85C, RH=85%,  
Bias (V=80%rated or 100V max) for 1008hrs (Sample size: 80 units/lot)

High Temperature Reverse Bias: Ta=150C, Bias(V=80%rated) for 1008hrs (Sample size: 80 units/lot)

Intermittent Operating Life: Ta = 25C, Ton/Toff=3.5 min,  
delta Tj = 100C, 8572 cycles (Sample size: 80 units/lot)

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Temp Cycle: Ta=-65C/150C, Air to air, Dwell>=10min for 1000 cycles  
(Sample size: 80 units/lot)

Autoclave: Ta=121C, P=15psig, RH=100% for 96hrs (Sample size: 80 units/lot)

Electical Characterization at -40C, +25C, and +150C cycles (Sample size: 25 units/lot)

**AFFECTED DEVICE LIST (WITHOUT SPECIALS):****PART**

2N6070A  
2N6071A  
2N6071B  
2N6071BT  
2N6073A  
2N6073B  
2N6075A  
2N6075B  
C106B  
C106D  
C106D1  
C106M  
C106M1  
MCR106-006  
MCR106-008  
T2322B  
TPA0234